

Notice of References Cited	Application/Control No. 10/797,514		Applicant(s)/Patent Under Reexamination KRAUS ET AL.	
	Examiner John Kim		Art Unit 1723	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0036637	02-2003	Fulton, Scott	530/363
*	B	US-2005/0282734	12-2005	Kadima et al.	514/002
*	C	US-5,440,018	08-1995	Ohmura et al.	530/363
*	D	US-5,962,649	10-1999	Noda et al.	530/364
*	E	US-5,849,874	12-1998	van der Laken et al.	530/364
*	F	US-4,990,447	02-1991	Konig et al.	435/71.1
*	G	US-2003/0026845	02-2003	Etzel et al.	424/535
*	H	US-2005/0215765	09-2005	Belew, Makonnen	530/363
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.